

•General Description

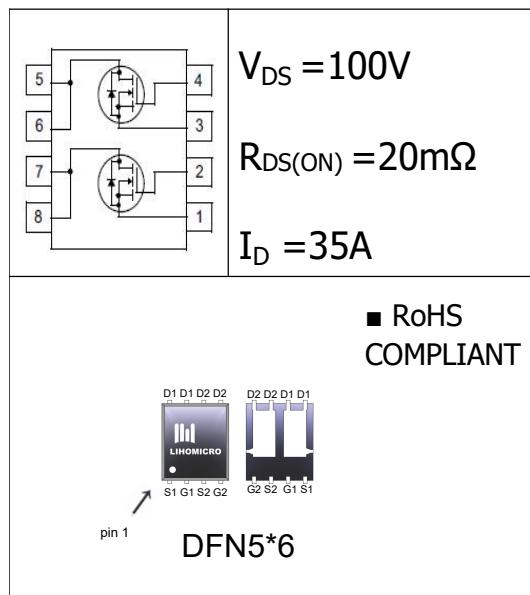
The SGT MOSFET LH024ND100 has the low $R_{DS(on)}$, low gate charge, fast switching and excellent avalanche characteristics. This device is suitable for fast charge and lighting.

•Features

- Fast switching
- Low $R_{DS(on)}$ & FOM

•Application

- LED/LCD/PDP TV and monitor Lighting
- Power Supplies


•Ordering Information:

Part Number	LH024ND100		
Package	DFN5*6		
Basic Ordering Unit (pcs)	5000		
Normal Package Material Ordering Code	LH024ND100N-DFN5*6-TAP		
Halogen Free Ordering Code	LH024ND100N-DFN5*6-TAP-HF		

•Absolute Maximum Ratings (TC = 25°C)

PARAMETER	SYMBOL	Value	UNIT
Drain-Source Breakdown Voltage	BV _{DSS}	100	V
Gate-Source Voltage	V _{GS}	±20	V
Continuous Drain Current ,T _C = 25°C	I _D	35	A
Pulsed drain current (TC = 25°C, tp limited by Tjmax) ¹	I _D pulse	105	A
Single Pulse Avalanche Energy ²	E _{AS}	72	mJ
Power Dissipation(TC=25°C)	P _D	52	W
Operating Temperature	T _J	-55~+150	°C
Storage Temperature	T _{STG}	-55~+150	°C

• Electronic Characteristics

PARAMETER	SYMBOL	TEST CONDITION	MIN	TYP	MAX	UNIT
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS} = 0V, I_D = 250\mu A$	100	--	--	V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	1.0	--	2.5	V
Drain-source On Resistance ³	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 10A$	--	20	24	$m\Omega$
		$V_{GS} = 4.5V, I_D = 6A$	--	25	32	
Drain-Source Leakage Current	I_{DSS}	$V_{DS} = 100V, V_{GS} = 0V, T_J = 25^\circ C$	--	--	1	μA
		$V_{DS} = 80V, V_{GS} = 0V, T_J = 85^\circ C$	--	--	10	
Gate-Source Leakage Current	I_{GSS}	$V_{GS} = \pm 20V, V_{DS} = 0V$	--	--	± 100	nA
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 50V, f = 1.0MHz$	--	780	--	pF
Output Capacitance	C_{oss}		--	132	--	
Reverse transfer Capacitance	C_{rss}		--	10	--	
Turn -Off Delay Time	$T_d(\text{off})$	$V_{GS} = 10V, I_D = 15.0A, R_G = 2.0\Omega$	--	18	--	ns
Turn-on delay time	$T_d(\text{on})$		--	11.5	--	
Rise time	T_r		--	2.8	--	
Fall time	T_f		--	3.2	--	
Total Gate Charge	Q_g	$I_D = 10A, V_{DS} = 50V, V_{GS} = 10V$	--	22	--	nC
Gate-to-Source Charge	Q_{gs}		--	7.8	--	
Gate-to-Drain Charge	Q_{gd}		--	3.5	--	
Continuous Diode Forward Current	I_s	--	--	--	35.0	A
Pulsed Diode Forward Current	I_{SM}	--	--	--	105.0	A
Diode Forward Voltage	V_{SD}	$T_J = 25^\circ C, I_s = 10.0A, V_{GS} = 0V$	--	--	1.3	V
Reverse Recovery Time	trr	$I_f = I_s, dI_f/dt = 100A/\mu s$	--	51	--	ns
Reverse Recovery Charge	Q_{rr}		--	110	--	μC
Peak Reverse Recovery Current	I_{RRM}		--	2.5	--	A

• Thermal Characteristics

PARAMETER	SYMBOL	MAX	UNIT
Thermal Resistance Junction-case	R_{thJC}	2.4	$^\circ C/W$
Thermal Resistance Junction-ambient	R_{thJA}	62	$^\circ C/W$

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.

2. $I_{AS} = 17A, V_{DD} = 50V, R_G = 25\Omega, \text{Starting } T_J = 25^\circ C$

3. Pulse Test : Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$

•Typical Characteristics

Figure 1.Typical output characteristics

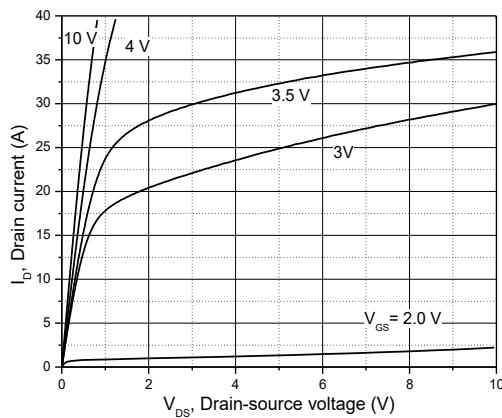


Figure 2. Typical transfer characteristics

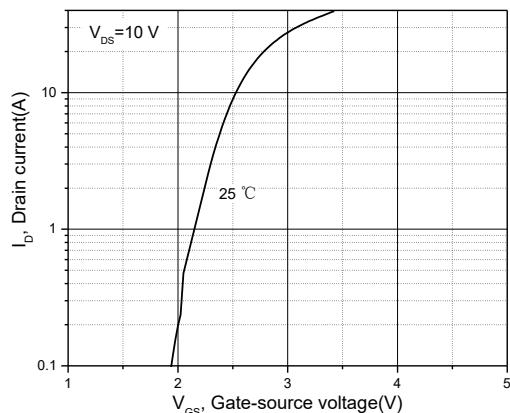


Figure 3. Typical capacitances

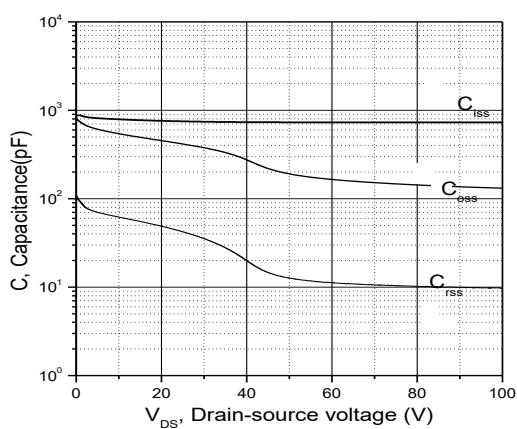


Figure 4. Typical gate charge

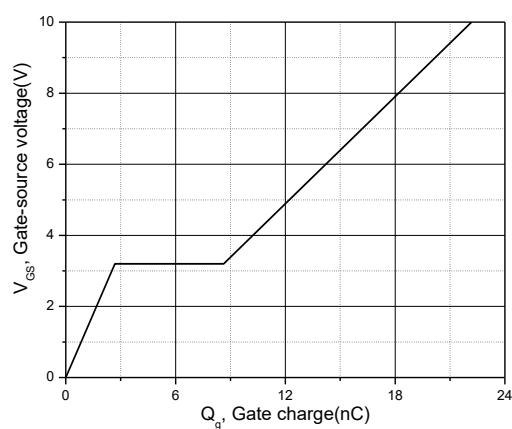


Figure 5. Drain-source breakdown voltage

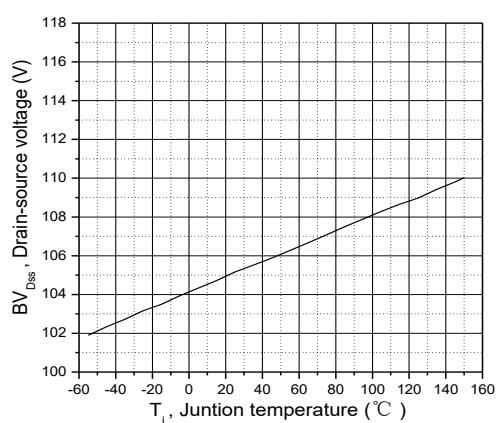
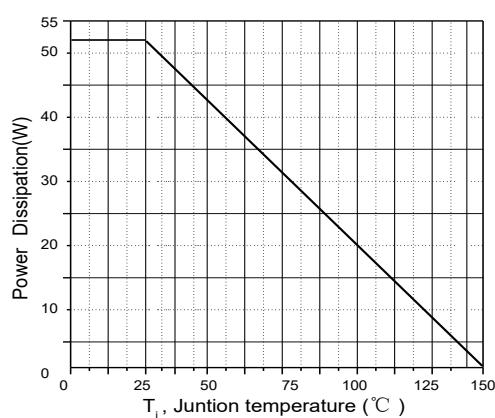


Figure 6. Power Dissipation(W)



● **Typical Characteristics**(cont.)

Figure 7. Forward characteristic of body diode

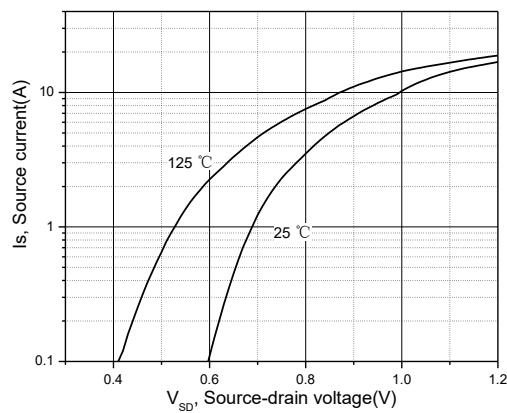


Figure 8. Drain-source on-state resistance

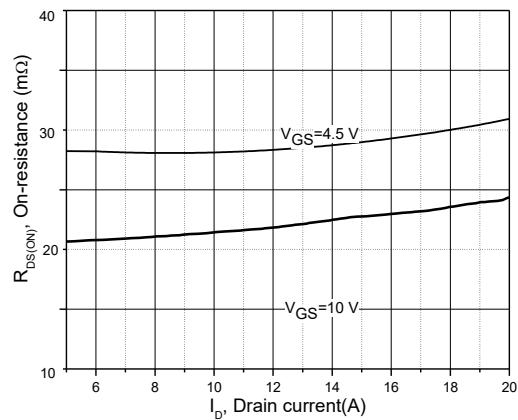
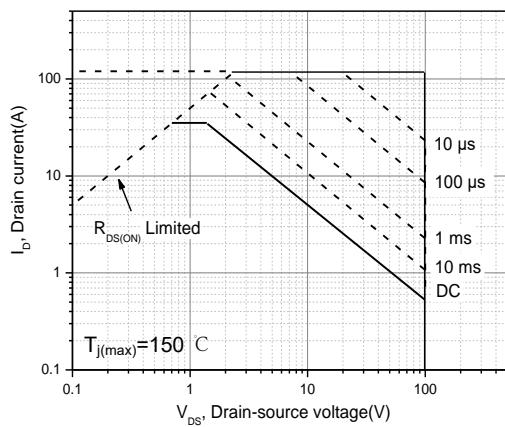


Figure 9. Safe operation area T_C=25 °C



•Test Circuit and Waveforms

Figure 1. Gate charge test circuit & waveform

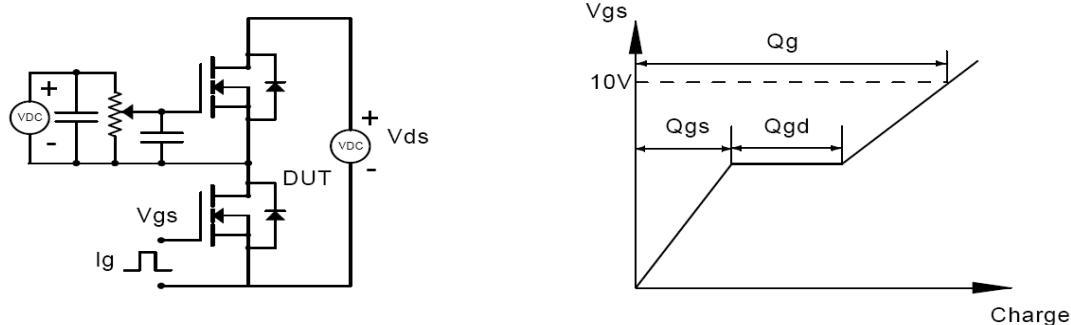


Figure 2. Switching time test circuit & waveforms

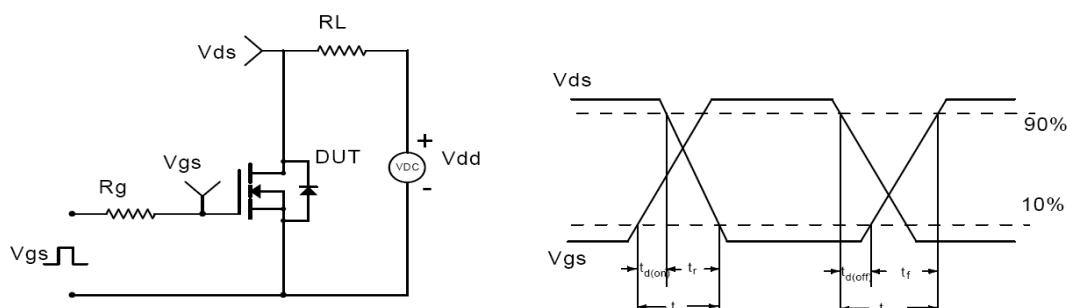


Figure 3. Unclamped inductive switching (UIS) test circuit & waveforms

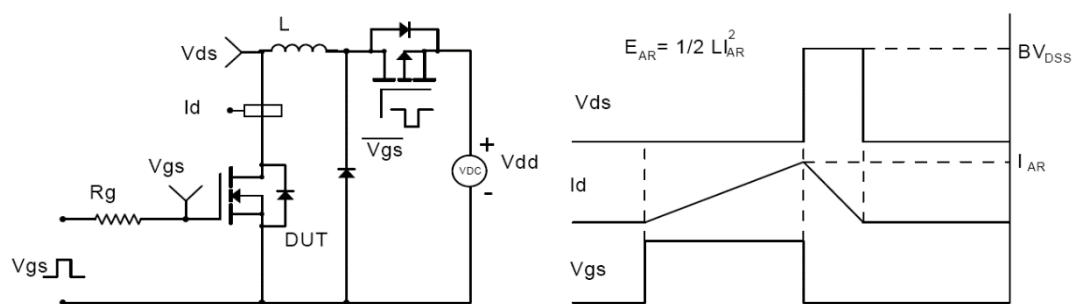
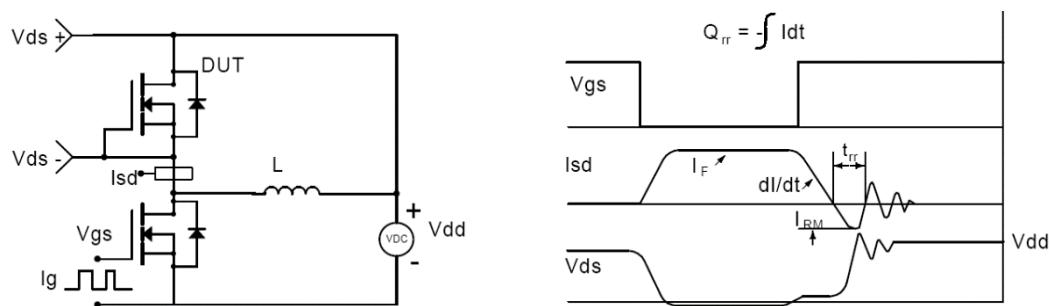


Figure 4. Diode reverse recovery test circuit & waveforms



• Dimensions (DFN5*6)

Unit: mm

SYMBOL	min	max	SYMBOL	min	max
A	1.00	1.20	E1	5.90	6.40
b	0.30	0.50	e	1.27BSC	
c	0.20	0.30	L	0.05	0.30
D	4.80	5.20	L1	0.40	0.80
D1	3.90	4.30	L2	1.20	2.00
D2	1.50	1.90	H	3.30	3.80
D3	0.40	0.80	I	-	0.18
E	5.50	5.90			

